

Resource Summary Report

Generated by T1D on Aug 12, 2026

JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM)

RRID:SCR_020196

Type: Tool

Proper Citation

JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM)
(RRID:SCR_020196)

Resource Information

URL: <https://www.jeolusa.com/PRODUCTS/Scanning-Electron-Microscopes-SEM/Soft-X-ray-Emission-Spectrometer>

Proper Citation: JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM) (RRID:SCR_020196)

Description: Scanning electron microscope that provides excellent light element detection and superb sensitivity that is best for chemical shift analysis of light elements

Resource Type: instrument resource

Keywords: Jeol, JEOL, Scanning Electron Microscope, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM)

Resource ID: SCR_020196

Alternate IDs: Model_Number_Soft X-Ray Emission Spectrometer

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260808T190149+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM).

No alerts have been found for JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM).

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.